Quad 8-Bit, 65 MSPS
Serial LVDS 3V A/D Converter

## FEATURES

- Four ADCs in one package
- Serial LVDS digital output data rates up to 520 Mbps (ANSF 644)
- Data clock output provided
- $\operatorname{SNR}=47 \mathrm{~dB}$ (to Nyquist)
- Excellent Linearity:

$$
\begin{aligned}
& \text { DNL }= \pm 0.25 \text { LSB (Typical) } \\
& \text { INL }= \pm 0.5 \text { LSB (Typical) }
\end{aligned}
$$

- 400 MHz full power analog bandwidth
- Power dissipation $=112 \mathrm{~mW}$ Core ADC Power
per channel at 65 MSPS
- $1 \mathrm{Vpp}-2 \mathrm{Vpp}$ input voltage range
- +3.0 V supply operation
- Power down mode


## APPLICATIONS

- Tape drives
- Medical imaging


## PRODUCT DESCRIPTION

The AD9289 is a quad 8-bit, 65 MSPS analog-to-digital converter with an on-chip track-and-hold circuit and is designed for low cost, low power, small size and ease of use. The product operates up to 65 MSPS conversion rate and is optimized for outstanding dynamic performance where a small package size is critical.

The ADC requires a single +3 V power supply and an LVDS compatible sample rate clock for full performance operation. No external reference or driver components are required for many applications. A separate output power supply pin supports LVDS compatible serial digital output levels.

The ADC automatically multiplies up the sample rate clock for the appropriate LVDS serial data rate. An FCO trigger is provided to signal a new output byte. Power down is supported, and the ADC consumes less than 10 mW when enabled.

Fabricated on an advanced CMOS process, the AD9289 is available in a 64 -ball mini-BGA package ( 64 CSP_BGA) specified over the industrial temperature range $\left(-40^{\circ} \mathrm{C}\right.$ to $\left.+85^{\circ} \mathrm{C}\right)$.

FUNCTIONAL BLOCK DIAGRAM


## PRODUCT HIGHLIGHTS

1. Four analog-to-digital converters are contained in one small, space saving package.
2. A Data Clock Out (DCO) is provided which operates up to 260 MHz .
3. The outputs of each ADC are serialized and provided on the rising and falling edge of DCO). Output data rates up to 520 Mbps ( 8 bits x 65 MSPS) are available.
4. The AD9289 operates from a single 3V power supply.
5. The clock duty cycle stabilizer maintains performance over a wide range of input clock duty cycles


Figure 2. Measured FFT

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## REVISION HISTORY

Revision PrA: Initial Version
Revision PrB: Updated specifications
Revision PrC: Added application section
Revision PrD: Revised block diagram, added LOCK/ output to timing diagram, added offset and gain matching definitions, updated Theory of Operation

Revision PrE: Updated timing diagram and PLL description
Revision PrF: Updated Timing Specs, Pin Function Description (Added DNC pins), Added Pin Configuration Diagram and Package Outline Revision PrG: Added DCR pin info, updated lvdsbias resistor value,

Revision H: Updated reference description, Removed S3, Added scope plot, Added FFT, Updated Tpd, Tcpd, Tmsb, Power, Updated LVDSBIAS Resistor value, Min Encode $\rightarrow$ 20MSPS

Revision I: Updated Power Supply Range, Added thermal impedance number,
Revision J: Added CML description, Modified Timing Diagram, Changed MSB naming to FCO,Removed S2, Modified Tpd,

## AD9289- SPECIFICATIONS ${ }^{1}$

AVDD $=3.0 \mathrm{~V}$, DRVDD $=3.0 \mathrm{~V}$; INT REF; DIFFERENTIAL ANALOG AND CLOCK INPUTS

| Parameter |  | Temp | Test Level | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| RESOLUTION |  |  |  |  | 8 |  | Bits |
| ACCURACY | No Missing Codes | Full | VI |  | Guaranteed |  |  |
|  | Offset Matching | $25^{\circ} \mathrm{C}$ | I |  | $\pm 25$ |  | mV |
|  | Gain Matching ${ }^{2}$ | $25^{\circ} \mathrm{C}$ | I |  | $\pm 2$ |  | \% FS |
|  | Differential Nonlinearity (DNL) | $\begin{gathered} 25^{\circ} \mathrm{C} \\ \text { Full } \end{gathered}$ | $\begin{gathered} \hline \mathrm{I} \\ \mathrm{VI} \end{gathered}$ |  | $\pm 0.25$ |  | $\begin{aligned} & \text { LSB } \\ & \text { LSB } \end{aligned}$ |
|  | Integral Nonlinearity (INL) | $\begin{gathered} \hline 25^{\circ} \mathrm{C} \\ \text { Full } \end{gathered}$ | $\begin{gathered} \hline \mathrm{I} \\ \mathrm{VI} \end{gathered}$ |  | $\pm 0.5$ |  | $\begin{aligned} & \hline \text { LSB } \\ & \text { LSB } \end{aligned}$ |
| TEMPERATURE DRIFT | Offset Error | Full | V |  | $\pm 16$ |  | ppm $/{ }^{\circ} \mathrm{C}$ |
|  | Gain Error ${ }^{2}$ | Full | V |  | $\pm 150$ |  | ppm $/{ }^{\circ} \mathrm{C}$ |
|  | Reference | Full | V |  |  |  | ppm $/{ }^{\circ} \mathrm{C}$ |
| REFERENCE | Internal Reference Voltage | $25^{\circ} \mathrm{C}$ | I |  | 0.5 |  | V |
|  | Output Current | Full | V |  |  |  | uA |
|  | Input Current | Full | V |  |  |  | uA |
|  | Input Resistance | Full | V |  | 7 |  | $\mathrm{k} \Omega$ |
| ANALOG INPUTS | Differential Input Voltage Range |  |  |  | 1-2 |  | Vpp |
|  | Common Mode Voltage | Full | V |  | 1.5 |  | V |
|  | Input Resistance | Full | V |  | tbd |  | k $\Omega$ |
|  | Input Capacitance | Full | V |  | 5 |  | pF |
|  | Analog Bandwidth, Full Power | Full | V |  | 400 |  | MHz |
| POWER SUPPLY | AVDD | Full | IV | 2.85 | 3.0 | 3.15 | V |
|  | DRVDD | Full | IV | 2.85 | 3.0 | 3.15 | V |
|  | Power Dissipation ${ }^{3}$ | Full | VI |  | 558 |  | mW |
|  | Power Down Dissipation | Full | VI |  | <10 |  | mW |
|  | Power Supply Rejection Ratio (PSRR) | $25^{\circ} \mathrm{C}$ | I |  |  |  | $\mathrm{mV} / \mathrm{V}$ |
|  | IAVDD $^{3}$ | Full | VI |  | 150 |  | mA |
|  | DRVDD $^{3}$ | Full | VI |  | 36 |  | mA |
| CROSSTALK | Crosstalk | Full | V |  | 70 |  | dB |

Table 1

[^0]
## DIGITAL SPECIFICATIONS

AVDD $=3.0 \mathrm{~V}$, DRVDD $=3.0 \mathrm{~V}$

| Parameter |  | Temp | Test | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CLOCK INPUTS(CLK+, CLK-) | Differential Input Voltage ${ }^{1}$ | Full | IV | 247 |  |  | mVpp |
|  | Input Common Mode Voltage | Full | IV |  | 1.25 |  | V |
|  | Input Resistance | Full | IV |  |  |  | $\mathrm{k} \Omega$ |
|  | Input Capacitance | $25^{\circ} \mathrm{C}$ | IV |  |  |  | pF |
| LOGIC INPUTS | Logic '1' Voltage | Full | IV | 2.0 |  |  | V |
|  | Logic '0' Voltage | Full | IV |  |  | 0.8 | V |
|  | Input Resistance | Full | IV |  | 30 |  | $\mathrm{k} \Omega$ |
|  | Input Capacitance | Full | IV |  | 4 |  | PF |
| DIGITAL OUTPUTS <br> (LVDS Mode) | Differential Output Voltage (VOD) | Full | IV | 247 |  | 454 | mV |
|  | Output Offset Voltage (V $\mathrm{V}_{\text {SS }}$ ) | Full | IV | 1.125 |  | 1.375 | V |
|  | Output Coding | Full | IV | Twos Complement or Binary |  |  |  |

Table 2: Digital Specifications

## AC SPECIFICATIONS ${ }^{2}$

AVDD $=3.0 \mathrm{~V}$, DRVDD $=3.0 \mathrm{~V}$; INTERNAL REF; DIFFERENTIAL ANALOG AND CLOCK INPUT, LVDS OUTPUT MODE

| Parameter |  | Temp | Test | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SIGNAL TO NOISE RATIO (SNR) Without Harmonics | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 47.5 |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 47.5 |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
| SIGNAL TO NOISE RATIO (SINAD) With Harmonics | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 47 |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 47 |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
| EFFECTIVE <br> NUMBER OF BITS (ENOB) | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 7.5 |  | Bits |
|  | $\mathrm{f}_{\mathrm{IN}}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | Bits |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 7.5 |  | Bits |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | Bits |
| SPURIOUS FREE DYNAMIC RANGE (SFDR) | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 62 |  | dB |
|  | $\mathrm{f}_{\text {IN }}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 59 |  | dB |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dB |
| SECOND AND THIRD HARMONIC DISTORTION | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 62 |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 59 |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dBc |
| TOTAL HARMONIC DISTORTION (THD) | $\mathrm{f}_{\mathrm{IN}}=10.3 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | 60 |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=19.6 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=32.5 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | I |  | 58 |  | dBc |
|  | $\mathrm{f}_{\mathrm{IN}}=51 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  |  | dBc |

[^1]| Parameter | Temp | Test <br> Level | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :--- | :--- | :--- | :--- |
| TWO TONE <br> INTERMOD <br> DISTORTION (IMD) | $\mathrm{f}_{\mathrm{I} 1}=19 \mathrm{MHz}, \mathrm{f}_{\mathrm{IN} 2}=20 \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  |  | dBc |
| $\mathrm{f}_{\mathrm{N} 1}=x \times \mathrm{MHz}, \mathrm{f}_{\mathrm{IN} 2}=x \times \mathrm{MHz}$ | $25^{\circ} \mathrm{C}$ | V |  | dBc |  |  |

Table 3: AC Specifications

## SWITCHING SPECIFICATIONS

AVDD $=3.0 \mathrm{~V}$, DRVDD $=3.0 \mathrm{~V}$; DIFFERENTIAL ENCODE INPUT

| Parameter |  | Temp | Test Level | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CLOCK | Maximum Clock Rate | Full | VI | 65 |  |  | MSPS |
|  | Minimum Clock Rate | Full | VI |  |  | 20 | MSPS |
|  | Clock Pulse Width High ( $\mathrm{t}_{\mathrm{EH}}$ ) | Full | IV | 6.9 |  |  | ns |
|  | Clock Pulse Width Low (teL) | Full | IV | 6.9 |  |  | ns |
| OUTPUT PARAMETERS IN LVDS MODE | Valid Time (tv) ${ }^{1}$ | Full | VI |  |  |  | ns |
|  | Propagation Delay (tpD) ${ }^{1}$ | Full | VI |  | 10 |  | ns |
|  | MSB Propagation Delay ( $\mathrm{t}_{\text {MSB }}$ ) ${ }^{1}$ | Full | VI |  | 10 |  | ns |
|  | Rise Time ( $\mathrm{t}_{\mathrm{R}}$ ) (20\% to 80\%) | Full | V |  | 0.5 |  | ns |
|  | Fall Time ( $\mathrm{t}_{\mathrm{F}}$ ) (20\% to 80\%) | Full | V |  | 0.5 |  | ns |
|  | DCO Propagation Delay (tcpi) | Full | VI |  | 10 |  | ns |
|  | Data to DCO Skew ( tPD - $\mathrm{t}_{\text {CPD }}$ ) | Full | IV |  | +/-100 |  | pS |
|  | Pipeline Latency | Full | VI |  | 6 |  | cycles |
| APERTURE | Aperture Delay ( $\mathrm{t}_{\mathrm{A}}$ ) | $25^{\circ} \mathrm{C}$ | V |  |  |  | ps |
|  | Aperture Uncertainty (Jitter) | $25^{\circ} \mathrm{C}$ | V |  | <1 |  | ps rms |

Table 4: Switching Specifications

## EXPLANATION OF TEST LEVELS

## TEST LEVEL

I $\quad 100 \%$ production tested.

II $\quad 100 \%$ production tested at $+25^{\circ} \mathrm{C}$ and guaranteed by design and characterization at specified temperatures.

III Sample Tested Only

IV Parameter is guaranteed by design and characterization testing.

V Parameter is a typical value only.

VI
$100 \%$ production tested at $+25^{\circ} \mathrm{C}$ and guaranteed by design and characterization for industrial temperature range.

[^2]ABSOLUTE MAXIMUM RATINGS

| Parameter | AVDD Voltage | Rating |
| :--- | :--- | :--- |
|  | DRVDD Voltage |  |
|  | Analog Input Voltage |  |
|  | Analog Input Current |  |
|  | Digital Input Voltage |  |
|  | Digital Output Current | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
|  | VREF Input Voltage |  |
|  | Operating Temperature Range (Ambient) |  |
|  | Maximum Junction Temperature |  |
|  | Lead Temperature (Soldering, 10 sec) | $40^{\circ} \mathrm{C} / \mathrm{W}$ |
|  | Maximum Case Temperature |  |
|  | Storage Temperature Range (Ambient) |  |

Table 5: Absolute Maximum Ratings
Stresses above those listed under the Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

[^3]
## DEFINITIONS

## ANALOG BANDWIDTH

The analog input frequency at which the spectral power of the fundamental frequency (as determined by the FFT analysis) is reduced by 3 dB .

## APERTURE DELAY

The delay between the $50 \%$ point of the rising edge of the ENCODE command and the instant at which the analog input is sampled.

## APERTURE UNCERTAINTY (JITTER)

The sample-to-sample variation in aperture delay.

## CROSSTALK

Coupling onto one channel being driven by a low level ( -40 dBFS ) signal when the adjacent interfering channel is driven by a fullscale signal.

## DIFFERENTIAL ANALOG INPUT RESISTANCE, DIFFERENTIAL ANALOG INPUT CAPACITANCE, AND DIFFERENTIAL ANALOG INPUT IMPEDANCE

The real and complex impedances measured at each analog input port. The resistance is measured statically and the capacitance and differential input impedances are measured with a network analyzer.

## DIFFERENTIAL ANALOG INPUT VOLTAGE RANGE

The peak to peak differential voltage that must be applied to the converter to generate a full scale response. Peak differential voltage is computed by observing the voltage on a single pin and subtracting the voltage from the other pin, which is 180 degrees out of phase. Peak to peak differential is computed by rotating the inputs phase 180 degrees and taking the peak measurement again. Then the difference is computed between both peak measurements.

## DIFFERENTIAL NONLINEARITY

The deviation of any code width from an ideal 1 LSB step.

## EFFECTIVE NUMBER OF BITS

The effective number of bits (ENOB) is calculated from the measured SNR based on the equation:

$$
E N O B=\frac{S N R_{\text {MEASURED }}-1.76 d B}{6.02}
$$

## CLOCK PULSE WIDTH/DUTY CYCLE

Pulse width high is the minimum amount of time that the Clock
pulse (CLK+) should be left in logic " 1 " state to achieve rated performance; pulse width low is the minimum time the clock pulse should be left in low state. See timing implications of changing $\mathrm{t}_{\mathrm{clk}}$ in text. At a given clock rate, these specs define an acceptable clock duty cycle.

## FULL SCALE INPUT POWER

Expressed in dBm . Computed using the following equation:

$$
\text { Power } \left._{\text {Fullscale }=10 \log \left(\frac{\frac{V_{\text {Fullscale }_{\text {mss }}}^{2}}{Z_{\text {Input }}}}{.001}\right), ~\left(\frac{101}{}\right.}\right)
$$

## GAIN ERROR

Gain error is the difference between the measured and ideal full scale input voltage range of the worst ADC.

## GAIN MATCHING

Expressed in \%FSR. Computed using the following equation:

$$
\text { GainMatching }=\frac{F S R_{\max }-F S R_{\min }}{\left(\frac{F S R_{\max }+F S R_{\min }}{2}\right)} * 100 \%
$$

where $\mathrm{FSR}_{\text {max }}$ is the most positive gain error of the ADCs and $\mathrm{FSR}_{\text {min }}$ is the most negative gain error of the ADCs.

## HARMONIC DISTORTION, SECOND

The ratio of the rms signal amplitude to the rms value of the second harmonic component, reported in dBc .

## HARMONIC DISTORTION, THIRD

The ratio of the rms signal amplitude to the rms value of the third harmonic component, reported in dBc .

## INTEGRAL NONLINEARITY

The deviation of the transfer function from a reference line measured in fractions of 1 LSB using a "best straight line" determined by a least square curve fit.

## MINIMUM CONVERSION RATE

The encode rate at which the SNR of the lowest analog signal frequency drops by no more than 3 dB below the guaranteed limit.

## MAXIMUM CONVERSION RATE

The encode rate at which parametric testing is performed.

## OFFSET ERROR

Offset error is the difference between the measured and ideal voltage at the analog input that produces the midscale code at the outputs. Offset error is given for the worst ADC.

## OFFSET MATCHING

Expressed in mV . Computed using the following equation:

$$
\text { OffsetMatching }=O F F_{\max }-\text { OFF } F_{\min }
$$

where $\mathrm{OFF}_{\text {max }}$ is the most positive offset error and $\mathrm{OFF}_{\text {min }}$ is the most negative offset error.

## OUTPUT PROPAGATION DELAY

The delay between a differential crossing of CLK+ and CLK- and the time when all output data bits are within valid logic levels.

## NOISE (FOR ANY RANGE WITHIN THE ADC)

$$
V_{n o i s e}=\sqrt{Z * .001 * 10^{\left(\frac{F S_{d B m}-S N R_{d B c}-\text { Signal }_{d B F S}}{10}\right)}}
$$

Where Z is the input impedance, FS is the full scale of the device for the frequency in question, SNR is the value for the particular input level and Signal is the signal level within the ADC reported in dB below full scale. This value includes both thermal and quantization noise.

## POWER SUPPLY REJECTION RATIO

The ratio of a change in input offset voltage to a change in power supply voltage.

## SIGNAL-TO-NOISE-AND-DISTORTION (SINAD)

The ratio of the rms signal amplitude (set 1 dB below full scale) to the rms value of the sum of all other spectral components, including harmonics but excluding dc.

## SIGNAL-TO-NOISE RATIO (WITHOUT HARMONICS)

The ratio of the rms signal amplitude (set at 1 dB below full scale) to the rms value of the sum of all other spectral components, excluding the first five harmonics and dc.

## SPURIOUS-FREE DYNAMIC RANGE (SFDR)

The ratio of the rms signal amplitude to the rms value of the peak spurious spectral component. The peak spurious component may or may not be a harmonic. It also may be reported in dBc (i.e., degrades as signal level is lowered) or dBFS (i.e., always related back to converter full scale).

## TWO-TONE INTERMODULATION DISTORTION REJECTION

The ratio of the rms value of either input tone to the rms value of the worst third order intermodulation product; reported in dBc .

## TWO-TONE SFDR

The ratio of the rms value of either input tone to the rms value of the peak spurious component. The peak spurious component may or may not be an IMD product. It also may be reported in dBc (i.e., degrades as signal level is lowered) or in dBFS (i.e., always relates back to converter full scale).

## WORST OTHER SPUR

The ratio of the rms signal amplitude to the rms value of the worst spurious component (excluding the second and third harmonic) reported in dBc .

## TRANSIENT RESPONSE TIME

Transient response time is defined as the time it takes for the ADC to reacquire the analog input after a transient from $10 \%$ above negative full scale to $10 \%$ below positive full scale.

## OUT-OF-RANGE RECOVERY TIME

Out of range recovery time is the time it takes for the ADC to reacquire the analog input after a transient from $10 \%$ above positive full scale to $10 \%$ above negative full scale, or from $10 \%$ below negative full scale to $10 \%$ below positive full scale.

## THEORY OF OPERATION

Each A/D converter in the AD9289 architecture consists of a frontend sample and hold amplifier (SHA) followed by a pipelined switched capacitor $\mathrm{A} / \mathrm{D}$ converter. The pipelined $\mathrm{A} / \mathrm{D}$ converter is divided into two sections, consisting of six 1.5 -bit stages and a final 3-bit flash. Each stage provides sufficient overlap to correct for flash errors in the preceding stages. The quantized outputs from each stage are combined into a final 8 -bit result in the digital correction logic. The pipelined architecture permits the first stage to operate on a new input sample while the remaining stages operate on preceding samples. Sampling occurs on the rising edge of the clock.

Each stage of the pipeline, excluding the last, consists of a low resolution flash A/D connected to a switched capacitor DAC and interstage residue amplifier (MDAC). The residue amplifier magnifies the difference between the reconstructed DAC output and the flash input for the next stage in the pipeline. One bit of redundancy is used in each one of the stages to facilitate digital correction of flash errors. The last stage simply consists of a flash A/D.

The input stage contains a differential SHA that can be configured as ac- or dc-coupled in differential or single-ended modes. The output-staging block aligns the data, carries out the error correction and passes the data to the output buffers.During power-down the output buffers go into a high-impedance state.

## Clock Input

Typical high-speed A/D converters use both clock edges to generate a variety of internal timing signals, and as a result may be sensitive to clock duty cycle. Commonly a $+/-5 \%$ tolerance is required on the clock duty cycle to maintain dynamic performance characteristics. The AD9289 contains a clock duty cycle stabilizer that retimes the non-sampling edge, providing an internal clock signal with a nominal $50 \%$ duty cycle. This allows a wide range of clock input duty cycles without affecting the performance of the AD9289. As shown in TPC XX, noise and distortion performance are nearly flat over at least a $+/-15 \%$ range of duty cycle. The stabilizer circuit can be bypassed by grounding input pin DCR. ( There is an internal 22 K ohm pull-up resistor)

The duty cycle stabilizer uses a delay-locked loop (DLL) to create the non-sampling edge. As a result, any changes to the sampling frequency will require approximately 100 clock cycles to allow the DLL to acquire and lock to the new rate. High-speed, highresolution $\mathrm{A} / \mathrm{Ds}$ are sensitive to the quality of the clock input. The degradation in SNR at a given full-scale input frequency $\left(\mathrm{f}_{\mathrm{A}}\right)$ due only to aperture jitter (tA) can be calculated with the following equation:
SNR degradation $=20 \times \log 10[1 / 2 \times p i \times f A \times$ $t A]$

In the equation, the rms aperture jitter, $t A$, represents the root sum square of all jitter sources, which include the clock input, analog input signal, and A/D aperture jitter specification. Undersampling applications are particularly sensitive to jitter.
The clock input should be treated as an analog signal in cases where aperture jitter may affect the dynamic range of the AD9289. Power supplies for clock drivers should be separated from the A/D
output driver supplies to avoid modulating the clock signal with digital noise. Low jitter, crystarcontrolled oscillators make the best clock sources. If the clock is generated from another type of source (by gating, dividing, or other methods), it should be retimed by the original clock at the last step.

## Analog Inputs

For best dynamic performance, the source impedances driving VIN+ and VIN- should be matched such that common-mode settling errors are symmetrical. These errors will be reduced by the common-mode rejection of the A/D.

## Voltage Reference

A stable and accurate 0.5 V voltage reference is built into the AD9289. The input range can be adjusted by varying the reference voltage applied to the AD9289, using either the internal reference or an externally applied reference voltage. The input span of the A/D tracks reference voltage changes linearly. The Shared Reference mode allows the user to connect the references from the quad ADC together externally for superior gain and offset matching performance. If the ADCs are to function independently, the reference decoupling can be treated independently and can provide superior isolation between the four channels. To enable Shared Reference mode, the SHARED_REF pin must be tied high and external differential references must be externally shorted. (REFT_A must be externally shorted to REFT_B and REFB_A must be shorted to REFB_B.) Note that channels A and B are referenced to REFT_A and REFB_A and channels C and D are referenced to REFT_B and REFB_B.


Figure 3. Shared Reference Mode

## Internal Reference Connection

A comparator within the AD9289 detects the potential at the SENSE pin and configures the reference into four possible states, which are summarized in Table I. If SENSE is grounded, the reference amplifier switch is connected to the internal resistor divider (see Figure 2), setting VREF to 1 V . Connecting the SENSE pin to VREF switches the reference amplifier output to the SENSE pin, completing the loop and providing a 0.5 V reference output. If a resistor divider is connected as shown in Figure 3, the switch will
again be set to the SENSE pin. This will put the reference amplifier in a non-inverting mode with the VREF output defined as follows:

$$
\mathrm{VREF}=.5 *(1+\mathrm{R} 2 / \mathrm{R} 1)
$$

In all reference configurations, REFT and REFB drive the ADC core and establish its input span. The input range of the ADC always equals twice the voltage at the reference pin for either an internal or an external reference.


Figure 4.Internal Reference Connection


Figure 5.Programmable Reference Connection

## External Reference Operation

The use of an external reference may be necessary to enhance the gain accuracy of the ADC or improve thermal drift characteristics. When multiple ADCs track one another, a single reference (internal or external) may be necessary to reduce gain matching errors to an acceptable level. A high precision external reference may also be selected to provide lower gain and offset temperature drift. External reference mode is chosen by tying SENSE pin to AVDD and driving VREF with external reference.

X

| Selected Mode | SENSE Voltage | Internal Switch Position | Resulting VREF (V) | Resulting Differential <br> Span (V p-p) |
| :--- | :--- | :--- | :--- | :--- |
| External Reference | AVDD | N/A | N/A | $2 \times$ External Reference |
| Internal | VREF | SENSE | 0.5 | 1.0 |
| Programmable | 0.2 V to VREF | SENSE | $0.5 \times(1+$ R2/R1) | $2 \times$ VREF |
| Internal | AGND to 0.2 V | Internal Divider | 1.0 | 2.0 |

Table 1 Reference Settings

## Digital Outputs

The AD9289's differentialoutputs conform to the ANSI-644 LVDS standard. To set the LVDS bias current, place a resistor (RSET is nominally equal to $3.8 \mathrm{k} \Omega$ ) to ground at the LVDSBIAS pin. The RSET resistor current ( $\sim 1.2 / \mathrm{RSET}$ ) is ratioed on-chip setting the output current at each output equal to a nominal 3.5 mA . A $100 \Omega$ differential termination resistor placed at the LVDS receiver inputs results in a nominal 350 mV swing at the receiver.

The AD9289's LVDS outputs facilitate interfacing with LVDS receivers in custom ASICs and FPGAs that have LVDS capability for superior switching performance in noisy environments. Single point-to-point net topologies are recommended with a $100 \Omega$ termination resistor as close to the receiver as possible. It is recommended to keep the trace length no longer than 3 inches and to keep differential output trace lengths as equal as possible.

The format of the output data can be selected as offset binary or twos complement. Pin S1 is used to set the format.

| S1 Mode | Data Format |
| :--- | :--- |
| AVDD | Twos Complement |
| AGND | Offset Binary |

Table 6: S1 Configuration

## Timing

Data from each A/D is serialized and provided on a separate channel. The data rate for each serial stream is equal to 8 -bits times the sample clock rate, with a maximum of 520 MHz ( 8 -bits x $65 \mathrm{MSPS}=520 \mathrm{MHz}$ ). The lowest typical conversion rate is 20 MSPS.

Two output clocks are provided to assist in capturing data from the AD9289. The data clock out (DCO) is used to clock the output data and is equal to four times the sampling clock (CLK) rate. Data is clocked out of the AD9289 on the rising and falling edges
of DCO. The FCO clock is used to signal the start of a new output byte and is equal to the sampling clock rate. See the Timing Diagram for more information.

## PLL $\overline{\text { LOCK Output }}$

The AD9289 contains an internal PLL that is used to generate the data clock out (DCO). When the PLL is locked, the LOCK/ signal will be low, indicating valid data on the outputs.

If for any reason the PLL loses lock, the LOCK/ signal will go high as soon as the lock circuitry detects an unlocked condition. While the PLL is unlocked, the data outputs and DCO will remain in the last known state. If the LOCK/ signal goes high in the middle of a byte, no data or DCO signals will be available for the rest of the byte. It will take at least $1 \mu$ s to regain lock if lock is lost.

Once the PLL regains lock, the DCO will start. The first valid data byte will be indicated by the FCO signal. See the Timing Diagram for more information.

## CML Pin

A common mode level output is available at F3. This output selfbiases to AVDD/2. This is a relatively high impedance output (two 5 K resistors in series between AVDD and ground) with an output impedance of 2.5 K which may need to be considered when using as a reference.

## Overange

The AD9289 has an Overange output available that indicates when the ADC is driven out of range. OR+ is driven high in overrange condition, with the digital outputs are clamped to all zeroes or all ones.Pin Function Descriptions

## Preliminary Technical Data

| Pin No. | Name | Description | Pin No. | Name | Description |
| :---: | :---: | :--- | :---: | :---: | :--- |
| C8 | CLK+ | Input Clock - True |  |  |  |
| D8 | CLK- | Input Clock - Complement | G8 | VIN+D | ADC D Analog Input - True |
| F2, E4, <br> F7 | AVDD | 3 V Analog Supply | F8 | VIN-D | ADC D Analog Input - Complement |
| G2, E5, <br> D7,E7,G7 | AGND | Analog Ground | C5 | DCO- | Data Clock Output - Complement |
| C3, C6 | DRVDD | 3 V Digital Output Supply | C4 | DCO+ | Data Clock Output - True |
| D3, D6 | DRGND | Digital Ground | C1 | FCO+ | Frame Clock Output (MSB Indicator) <br> True Output |
| H5 | VREF | Voltage Reference Input/Output | C2 | FCO- | Frame Clock Output (MSB Indicator) <br> Complement Output |
| H4 | SENSE | Reference Mode Selection | B1 | D1+A | ADC A True Digital Output |
| F4 | REFT_A | Differential Reference (Positive) | A1 | D1-A | ADC A Complement Digital Output |
| G4 | REFB_A | Differential Reference (Negative) | B3 | D1+B | ADC B True Digital Output |
| F5 | REFT_B | Differential Reference (Positive) | A3 | D1-B | ADC B Complement Digital Output |
| G5 | REFB_B | Differential Reference (Negative) | B5 | D1+C | ADC C True Digital Output |
| E8 | PDWN | Power Down Selection (set pin to <br> AVDD for power down) | A5 | D1-C | ADC C Complement Digital Output |
| C7 | S1 | Data Format | B7 | D1+D | ADC D True Digital Output |
| G1 | VIN+A | ADC A Analog Input - True | D1 | OR+ | Over Range True |
| F1 | VIN-A | ADC A Analog Input - Complement | D2 | OR- | Over Range Complement |
| H2 | VIN+B | ADC B Analog Input - True | H1 | LVDSBIAS | LVDS Bias Resistor Pin (3.8K to gnd) |
| H3 | VIN-B | ADC B Analog Input - Complement | G3 | SHARED_REF | Shared Reference Control Bit |
| H7 | VIN+C | ADC C Analog Input - True | F3 | CML | Common Mode Level Output ( = AVDD/2) |
| H6 | VIN-C | ADC C Analog Input - Complement | D4 | LOCK/ | PLL Lock Output |
| A2,A4,A6, <br> A8,B2,B4, <br> B6,B8,D5, <br> E1,E2,E3, <br> F6,G6,H8 | DNC <br> (Do Not <br> Connect) |  | E6 | DCR | Duty Cycle Control Enable Input <br> Logic Hi enables duty cycle control circuit <br> Logic Lo disables duty cycle control circuit |

Table 7: Pin Function Descriptions

- S1 has an internal on-chip pulldown resistor


## PIN CONFIGURATIONS



Figure 6: BGA Top View

TIMING DIAGRAM


Figure 7: Timing Diagram


## OUTLINE DIMENSIONS

## TOP VIEW



NOTES :
1.Controlling Dimensions are in Millimeters (mm
2. Dimensions per JEDEC Standards MO-205,

Variation BA .
3.Solder Ball Matrix is $8 \times 8$

SIDE VIEW


BOTTOM VIEW



T1tle: 64 MINI-BGA (4 Layer) $8 \times 8 \mathrm{~mm}$ Body, 0.80 mm Pitch Package Outline Customer

Figure 8: BGA Package Outline

| Dim | Min. | Nom. | Max |  | Dim | Min. | Nom. | Max |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| A | 1.35 | 1.55 | 1.70 |  | b | 0.45 | 0.50 | 0.55 |
| A1 | 0.25 | 0.34 |  |  | e | 0.80 BSC |  |  |
| A2 | 1.10 | 1.21 | 1.31 |  | aaa | 0.10 |  |  |
| D | 7.90 | 8.00 | 8.10 |  | bbb | 0.10 |  |  |
| D1 | 5.60 BSC |  |  |  | ddd | 0.12 |  |  |
| E | 7.90 | 8.00 | 8.10 |  | eee | 0.15 |  |  |
| E1 | 5.60 BSC |  |  |  | fff | 0.08 |  |  |

## ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

## Ordering Guide

| Model | Temperature Range | Description |
| :--- | :--- | :--- |
| AD9289BBC-65 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ (Ambient) | 64 CSP_BGA |
| AD9289BBC-65EB | $25^{\circ} \mathrm{C}$ (Ambient) | Evaluation Board |
| Table 8: Ordering Guide |  |  |

This datasheet has been download from:
www.datasheetcatalog.com
Datasheets for electronics components.


[^0]:    ${ }^{1}$ Specifications subject to change without notice
    ${ }_{3}^{2}$ Gain error and gain temperature coefficients are based on the ADC only (with a fixed 0.5 V external reference and a 1 V p-p differential analog input).
    ${ }^{3}$ Power dissipation measured with rated encode and a dc analog input (Out puts Static, IVDD $=0$.). Ivcc and Ivod measured with TBD MHz analog input @ 0.5 dBFS .

[^1]:    ${ }^{1}$ Clock Inputs are LVDS compatible .Clock Inputs require external DC bias and cannot be AC coupled.
    ${ }^{2}$ SNR/harmonics based on an analog input voltage of -0.5 dBFS referenced to a 1 Vpp full-scale input range.

[^2]:    ${ }^{1} t_{V}$ and $t_{P D}$ are measured from the transition points of the CLK input to the $50 \% / 50 \%$ levels of the digital outputs swing. The digital output load during test is not to exceed an ac load of 5 pF or a dc current of $\pm 40 \mu \mathrm{~A}$. Rise and fall times measured from $20 \%$ to $80 \%$.

[^3]:    ${ }^{1} \theta_{\mathrm{ja}}$ for a 4 layer PCB with solid ground plane in still air.

